IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

in re Application) PATENT APPLICATION		
Inventor(s):	Cleeves et al.)		
)	Art Unit:	2814
Application No.:	10/681,509)		
)	Examiner:	Howard Weiss
Filed:	October 7, 2003)		
)	Atty Docket	No. SAND-01135US0
Γitle:	UNIFORM SEEDING TO)		(formerly MA-108)
	CONTROL GRAIN AND)		
	DEFECT DENSITY OF)	Customer No. 64948	
	CRYSTALLIZED SILICON)		
	FOR USE IN SUB-MICRON	()		
	THIN FILM TRANSISTORS	3)		

RESPONSE TO OFFICE ACTION UNDER 37 C.F.R. § 1.111 TO ACCOMPANY REQUEST FOR CONTINUED EXAMINATION

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

To the Commissioner:

Applicants request continued examination under 37 CFR 1.114. The amended claims and remarks included herein constitute the required submission.

Amendments to the claims begin on page 2 of this paper.

Remarks begin on Page 11 of this paper.